

The Big Picture: CMOS Image Sensors From Zero to Billions and Beyond

Eric R. Fossum EECS Colloquium University of California at Berkeley September 9, 2015





CMOS Image Sensors Enable Billions of Cameras Each Year





Photography

- Camera phone
- Digital single lens reflex (DSLR)
- Mirrorless and Point-and-shoot

Video

- TV (0.3Mpix), HDTV (2Mpix) UDTV (133Mpixel)
- Webcam
- High speed slow motion
- Motion capture
- Glass
- Body cam

Medical

- Endoscopy
- Pill camera
- **Dental X-rays**

Machine Vision

- Automotive
- Security
- Inspection

3D ranging

Gesture control

Etc.







Many kinds of digital cameras

















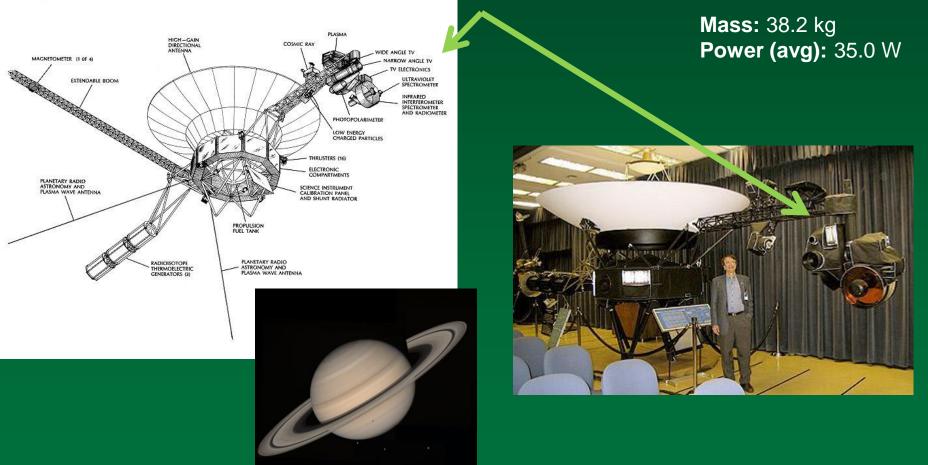
Inventions





"Necessity is the Mother of Invention"

Voyager (1977) ISS had vidicon cameras (wide angle and narrow angle)



© E.R. Fossum 2015

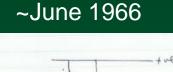
http://nssdc.gsfc.nasa.gov/nmc/experimentDisplay.do?id=1977-084A-01

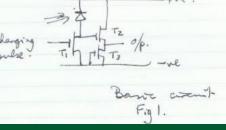


MOS "Photomatrices" 0th Generation Image Sensor

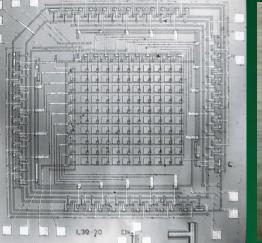


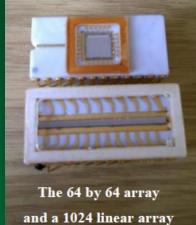
Peter JW Noble





First self-scanned → Sensor 10x10 1966/67







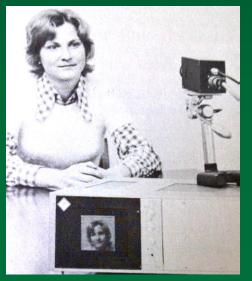
Gene Weckler

Mid-late 1960's MOS arrays at Plessey with startup Integrated Photomatrix Ltd. (IPL)





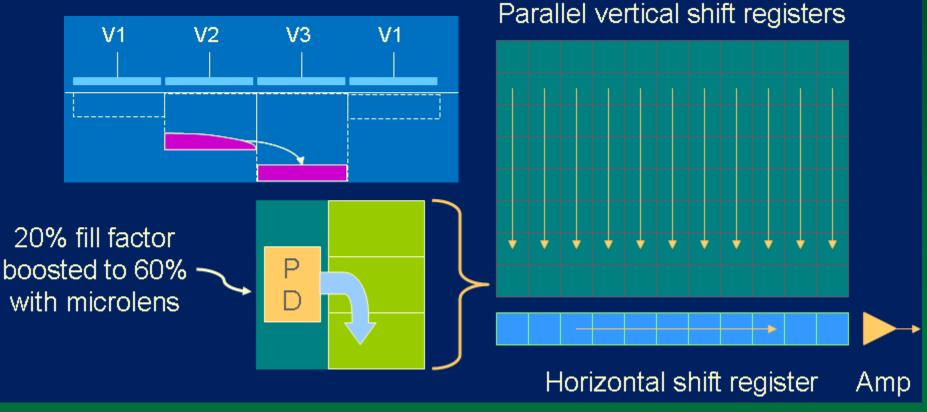
And Fairchild with startup Reticon





Charge-Coupled Device 1st Generation Image Sensor

MOS-based charge-coupled devices (CCDs) shift charge one step at a time to a common output amplifier (1969 Bell Labs)





2009 Nobel Prize in Physics

held on Seal 3. 1969 and the basis 510 n-types: letion regio we voltage applie nena The above i the vo (4

Figure 4. Original notes from the Boyle and Smith's brainstorm meeting on September 8 1969, when they made the first sketch of a CCD.

http://www.nobelprize.org/nobel_prizes/physics/laureates/2009/popularphysicsprize2009.pdf



Photo: U. Montan Willard S. Boyle



George E. Smith



"for the invention of an imaging semiconductor circuit – the CCD sensor"

CCD image sensor inventor: Michael F. Tompsett US patent no. 4,085,456 National Medal of Technology and Innovation 2010

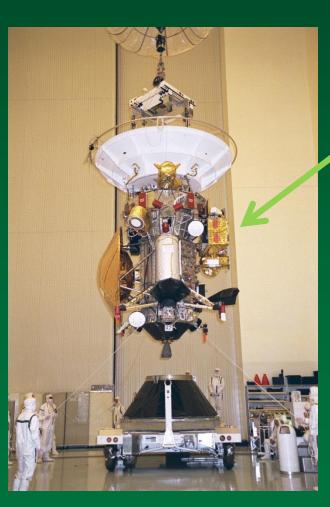


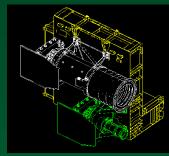




Gassini (1997) ISS has CCD cameras (wide angle and narrow angle)

Mass: 57.83 kg Power (avg): 30.0 W CCD: 1024x1024 pixels







December 18, 2012



NASA's Administrator Daniel Goldin "Faster, Better, Cheaper"



- Electronics integration is well-worn path to miniaturization, and MOSbased image sensors predate CCDs (e.g. Peter Noble or Gene Weckler late 1960's) including passive pixel and active pixel (3T) configurations.
- BUT MOS image quality is quite poor compared to CCDs due to temporal noise, fixed pattern noise and other artifacts.
- How to make a high performance image sensor in a mainstream CMOS process?

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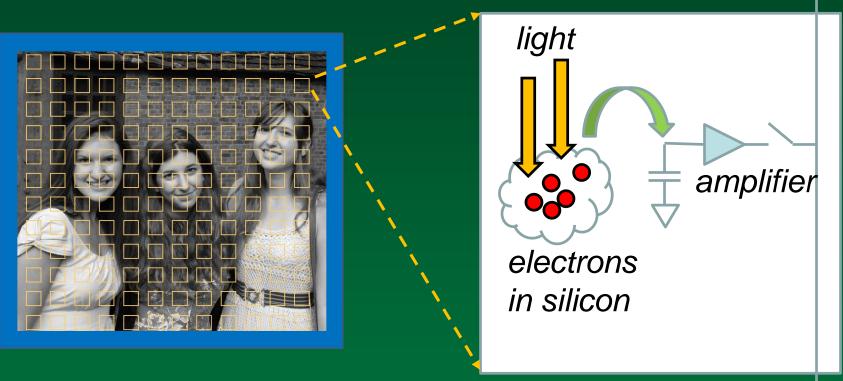
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SCHOOL

RTMOUT

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Active Pixels with Intra-Pixel Charge Transfer



- Complete charge transfer to suppress lag
- Correlated double-sampling to suppress kTC noise

OF

- Double-delta sampling to suppress fixed pattern noise
- On-chip ADC, timing and control, etc.

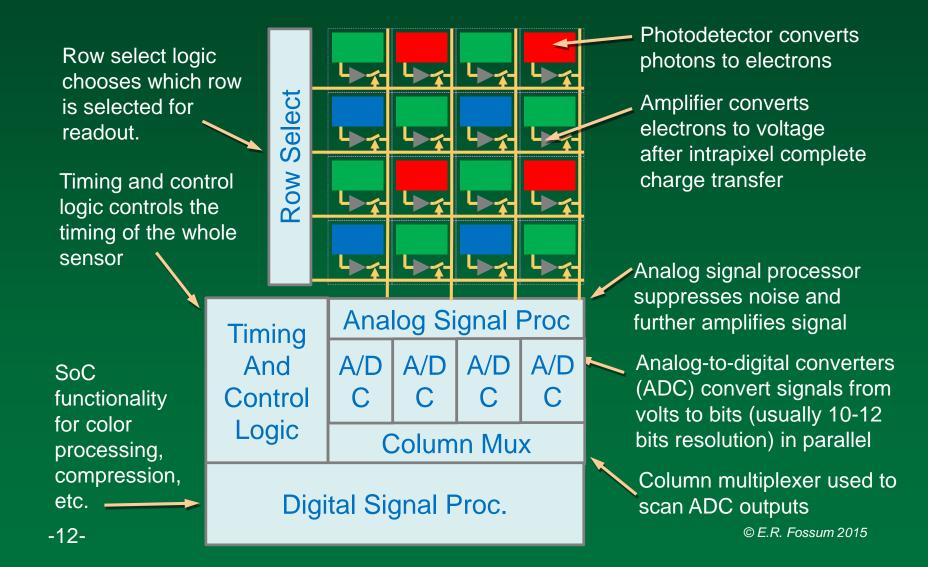
One

pixel



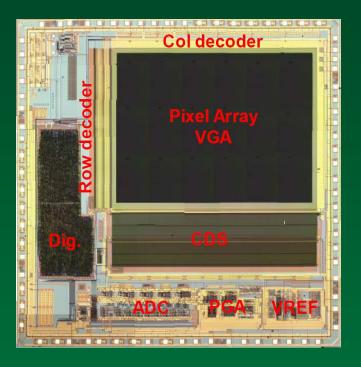


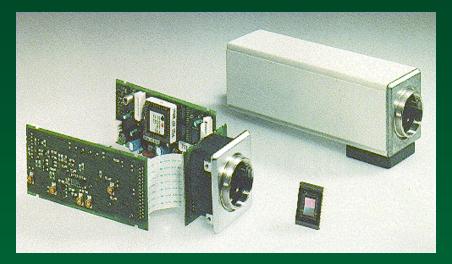
CMOS "Camera on a Chip" 2nd Generation Image Sensor Read pixel signals out thru switches and wires





Camera-on-a-Chip Enables Much Smaller Cameras







CMOS Active Pixel Sensor With Intra-Pixel Charge Transfer Camera-on-a-chip



Siimpel AF camera module 2007



Most of the JPL Team



Advanced Imager Technology Group, Jet Propulsion Laboratory, California Institute of Technology 1995 Back row: Roger Panicacci, Barmak Mansoorian, Craig Staller, Russell Gee, Peter Jones, John Koehler Front row: Robert Nixon, Quisup Kim, Eric Fossum, Bedabrata Pain, Zhimin Zhou, Orly Yadid-Pecht



Commercialization





Technology Transfer

Entrenched industry moves slowly in adopting new technologies so in February 1995 we founded **Photobit Corporation** to commercialize the CMOS image sensor technology ourselves





S.Kemeny, N. Doudoumopoulos, E. Fossum, R. Nixon



Perspiration Phase

1995-2001 Photobit grows to about 135 persons

- Self funded with custom-design contracts from private industry
- Important support from SBIR programs (NASA/DoD)
- Later, investment from strategic business partners to develop catalog products
- Over 100 new patent applications filed







The Photobit Team Circa 2000







Nov. 2001 – Photobit acquired by Micron Technology and license reverts back to Caltech

Meanwhile, by 2001 there were dozens of competitors emerging in the CMOS image sensor business due in part to the earlier efforts to promote the transfer the technology.

Examples: Toshiba, ST Micro, Omnivision

Micron becomes #1 in CMOS image sensor sales and market share

Later, came Sony and Samsung (now #1, #2 in worldwide market)

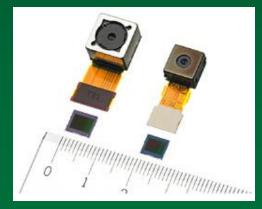
Micron spins out Aptina Aptina acquired by ON Semi, currently #4



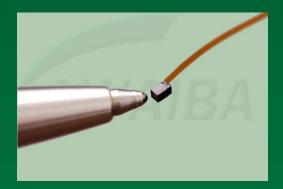


The Technology Develops a Life of its Own

- Today, over 2 billion cameras are manufactured each year that use the CMOS image sensor technology we invented at JPL, or more than 60 cameras per second, 24/7/52
- Semiconductor sales of CMOS image sensors will be \$10B/yr by 2016.
- Thousands of engineers working on this.
- Caltech has successfully enforced its patents against all the major players.
- NASA is now just adopting the technology for use in space.



16Mpix camera modules From Sony ~2012



Endoscopy Camera From Awaiba ~2012



New Technology Invariably Brings New Social Issues



Selfies and Instant Communications



Rapid Social Change (Arab Spring)



Drone Cameras



Body Cameras



Visual overload (e.g. Japanese Tsunami) -21-



Security v. Privacy



Inappropriate use © E.R. Fossum 2015

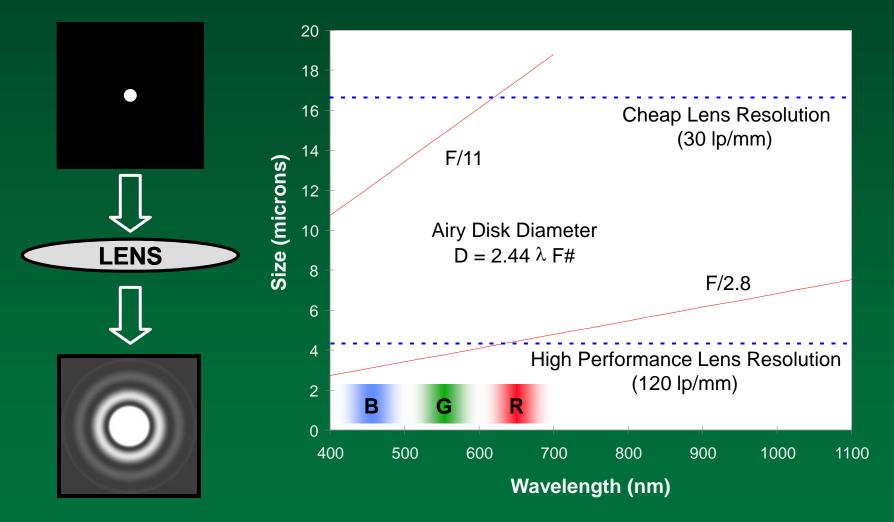


Some Science and Technology





Diffraction Limit

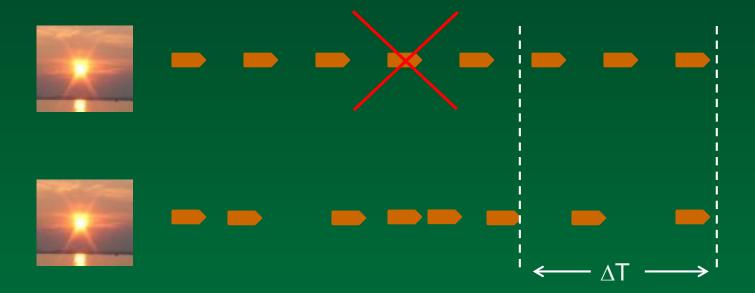


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Photon Shot Noise

 Photon emission is a Poisson process. Stream of photons is NOT regularly spaced.

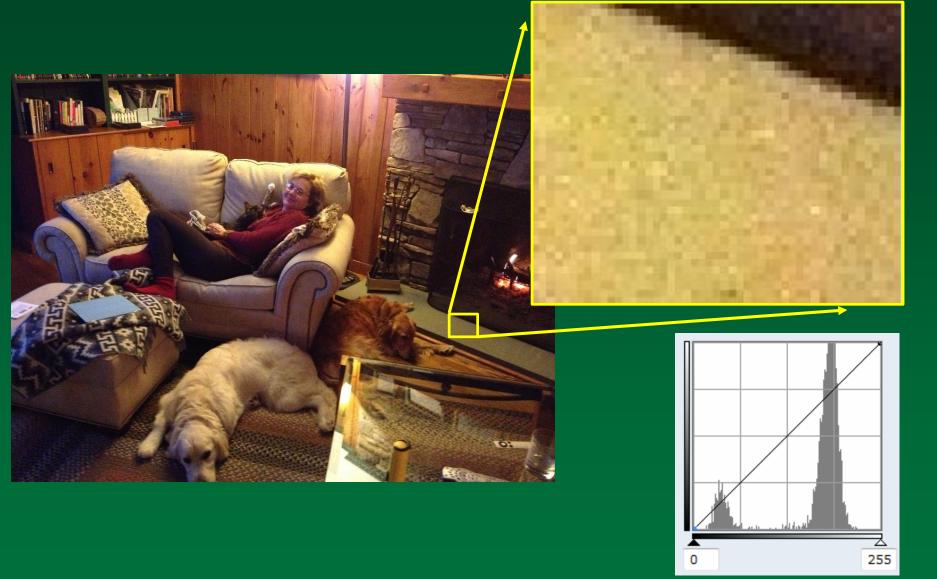


 Leads to variability when trying to determine average photon arrival rate. Gets better with longer measurement (more photons).





Photon Shot Noise in Pictures

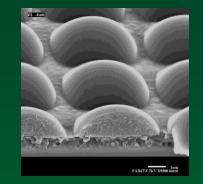




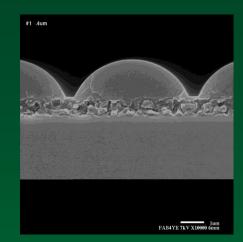
thayer school of ENGINEERING AT DARTMOUTH

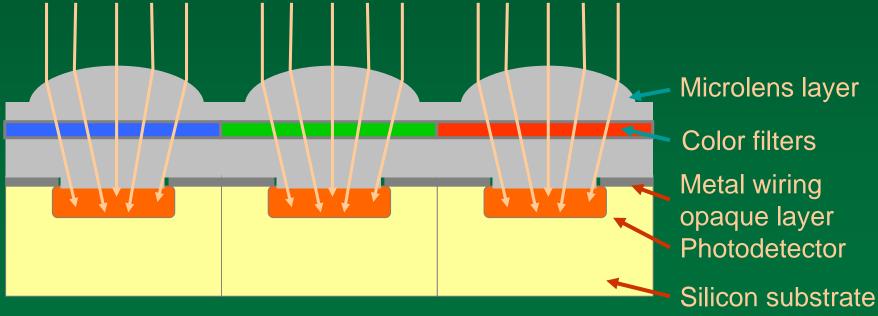
Microlenses

- Main camera lens brings image to microlenses
- Microlens funnels photons to active detector area.



Light Rays







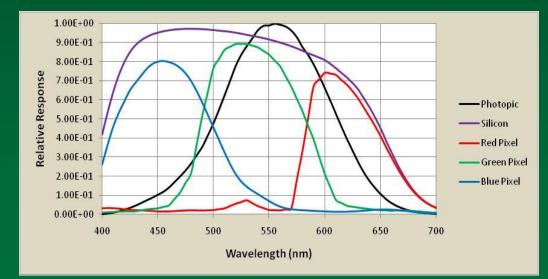


Color Filter Array (CFA)

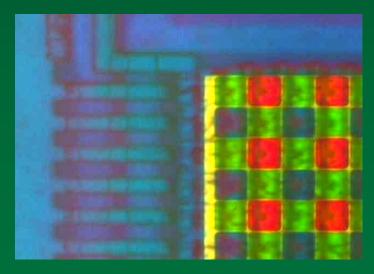
B

G

- Each pixel gets covered by a colored filter
 - We use red, green, blue (RGB) CFA best match for RGB displays
 - Pixel colors arranged in "Bayer" pattern GR



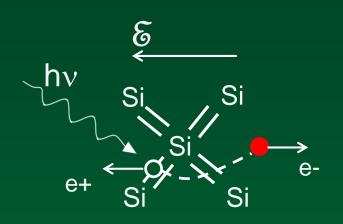
(assumes UV and NIR filters)



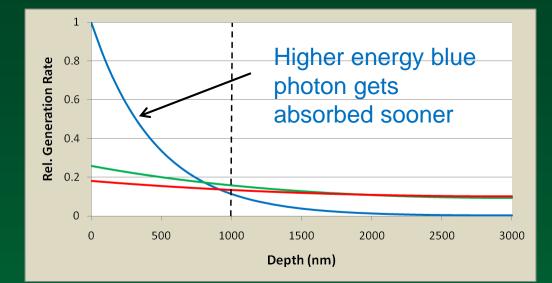


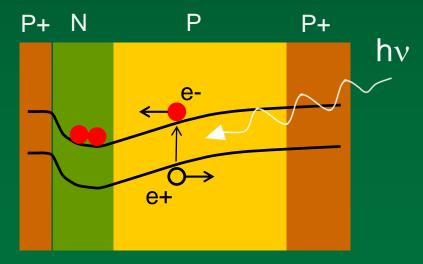
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Photons to Electrons



Covalently bonded silicon



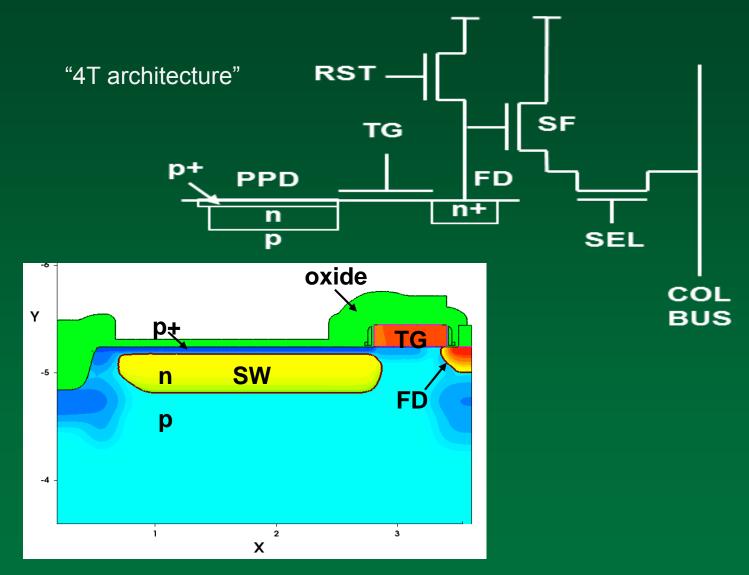


Pinned photodiode N. Teranishi et al.1982 for ILT CCD





CMOS Pinned Photodiode Pixel





E.R. Fossum and D. Hondongwa, A review of the pinned photodiode for CCD and CMOS image sensors, IEEE J. Electron Devices Society, vol 2(3) pp. 33-43 May 2014.



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Shared Readout Architecture

"1.35T architecture"

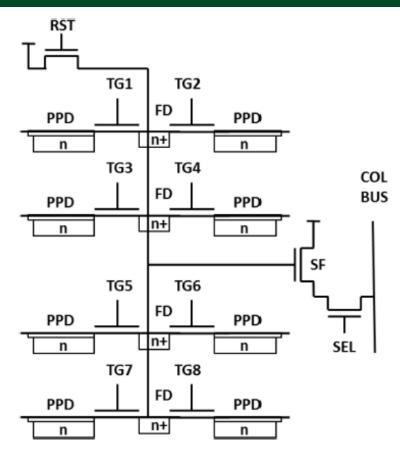
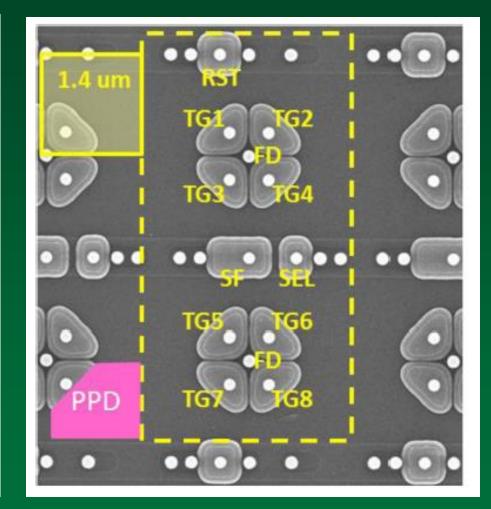


Fig. 9. 8-way shared readout 1.35T pixel schematic.

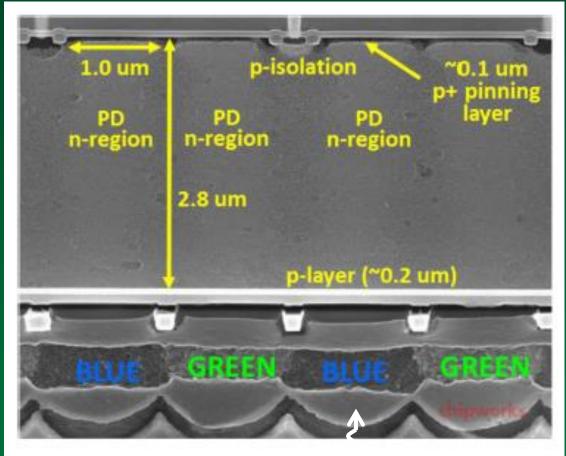


Sony 1.4 um BSI pixel





Backside Illumination (BSI)

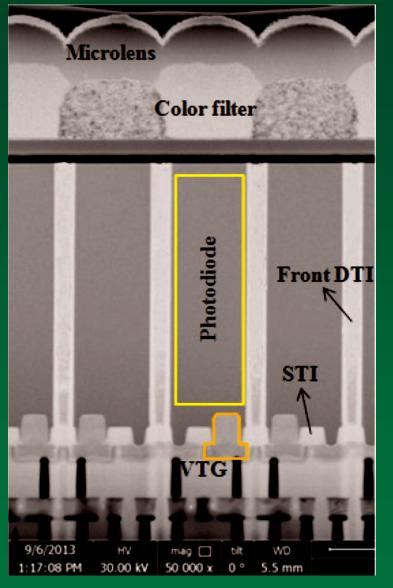


Sony 1.4 um BSI pixel





ENGINEERING Deep Trench Isolation for Crosstalk



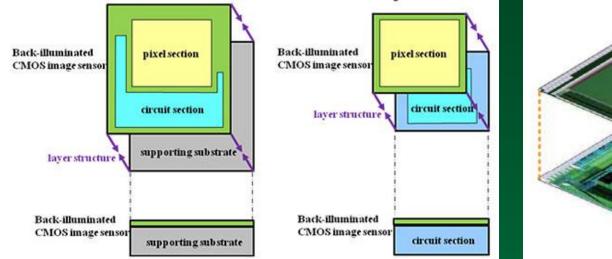
-32- Samsung ISOCELL ISSCC 2013

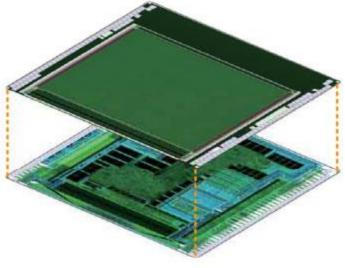


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Stacked CMOS BSI







http://www.chipworks.com/en/technicalcompetitive-analysis/resources/blog/sonyout-of-the-gate-with-isx014-stackedcamera-sensor/



Quanta Image Sensor

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Group at Dartmouth



L-R: Song Chen, Saleh Masoodian, Rachel Zizza, Donald Hondongwa, Dakota Starkey, Eric Fossum, Jiaju Ma, Leo Anzagira



- Additional Members
 - Arun Rao
 - Yue Song
 - Prof. Kofi Odame
 - Mike Guidash (Rambus)
 - Jay Endsley (Rambus)
 - Prof. Yue Lu (Harvard)
 - Prof. Atsushi Hamasaki (Hiroshima)
 - Mr. Ryohei Funatsu (NHK)

- QIS work supported, in large part, by
 - Rambus Inc.





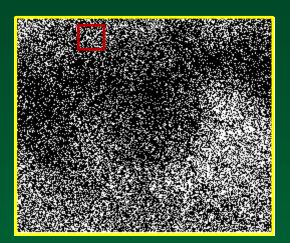
Quanta Image Sensor "Count Every Photon"

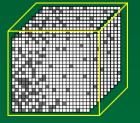
- Original goal for QIS was to take advantage of shrinking pixel size and make a very tiny, specialized pixel ("jot") which could sense a single photoelectron.
- Jots would be readout by scanning at a high frame rate to avoid likelihood of multiple hits in the same jot and loss of accurate counting.
- Image pixels could be created by combining jot data over a local spatial and temporal region using image processing.
- The first proposed algorithm was the "digital film sensor" using a "grain" and "digital development" construct.



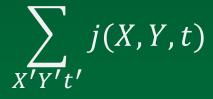
Pixels from Jots (Simulation)







Simplest



16x16x16 "cubicle" $0 \le S \le 4096$

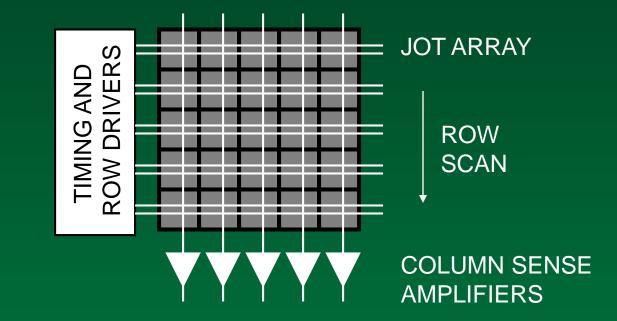


R. Zizza, Jots to Pixels: Image Formation Options for the Quanta Image Sensor, (Dartmouth, 2015)





QIS Core Architecture





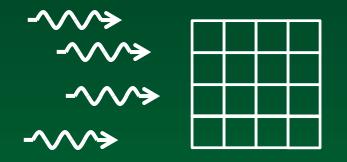


Figure of Merit: Flux Capacity ϕ_w

At the flux capacity, there is an average of one photoelectron per jot

 $\phi_w = j f_r / \sigma \bar{\gamma}$

 $j = jot \ density \ (per \ cm^2)$ $f_r = field \ readout \ rate \ (per \ sec)$ $\sigma = shutter \ duty \ cycle$ $\bar{\gamma} = average \ quantum \ efficiency$

• At 500nm jot pitch, 1000fps, 100% duty cycle and 35% QE, $\phi_w \cong 10^{12}/cm^2 s$

• Corresponds to ~100lux (555nm, F/2.8, RT=80%)

Drives high jot density and field readout rate so can handle normal lighting conditions

 \rightarrow And improve SNR per sq. cm of sensor area.



Multi-bit Jot Increases Flux Capacity

At the flux capacity, there is an average of $2^n - 1$ photoelectrons per *n*-bit jot

 $\phi_{wn} = jf_r(2^n - 1)/\sigma\bar{\gamma}$



Single bit jot 0, 1 electrons Multi-bit (2b) jot 0, 1, 2, 3 electrons

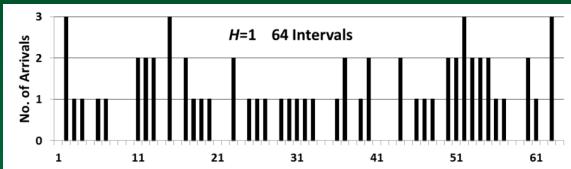
Can increase flux capacity at same jot density and field readout rate
Or, relax field readout rate and/or jot density for same flux capacity

Little impact on detector and storage well. Little impact on FD CG or voltage swing (e.g. 1mV/e -> 31mV swing for 5b jot. -41-



Photon and photoelectron arrival rate described by Poisson process

Define *quanta exposure* $H = \phi \tau$ T = 1 means expect 1 arrival on average.



Monte Carlo

For jot, only two states of interest $P[0] = e^{-H}$ $P[k > 0] = 1 - P[0] = 1 - e^{-H}$

Probability of k arrivals

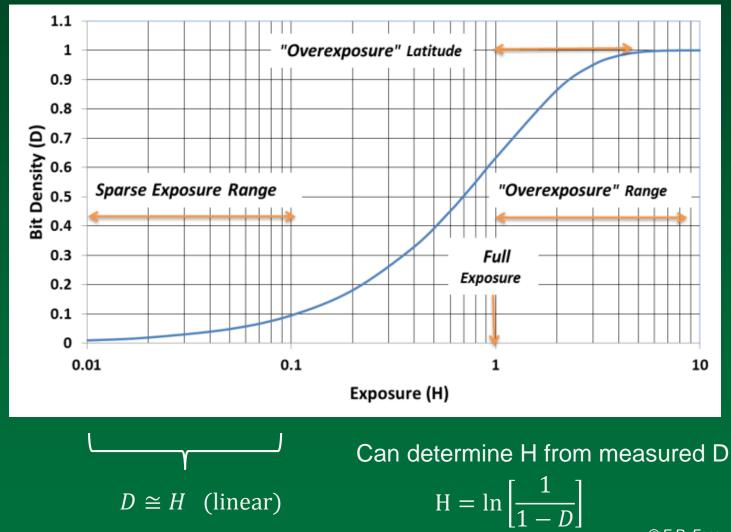
 $P[k] = \frac{e^{-H}H^k}{k!}$

For ensemble of *M* jots, the expected number of 1's : $M_1 = M \cdot P[k > 0]$



Bit Density

Bit Density
$$D \triangleq \frac{M_1}{M} = 1 - e^{-H}$$



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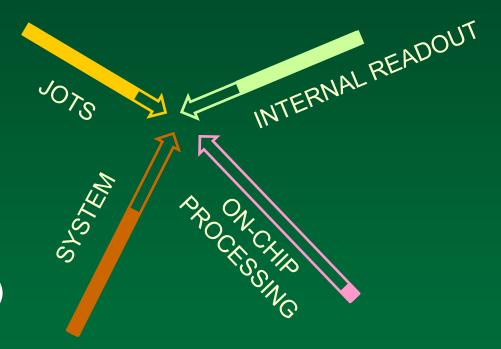




QIS implementation requires Devices, Circuits, and System

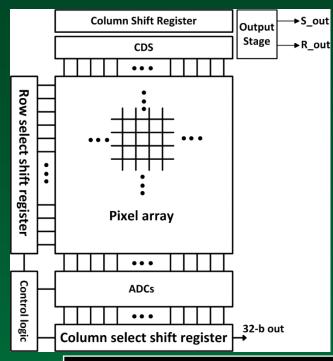
Strawman numbers

- <500 nm jot pitch</p>
- Gigajot QIS (10⁹ jots)
- 1000 fps
- 1 Tb/s data rate
- 1 Watt or less (<1pJ/b)</p>





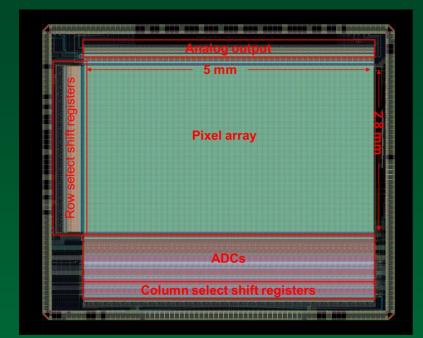
23mW 1000fps 1 Mpix binary image sensor



1 captured frame,≲10e-



Masoodian, Rao, Ma, Odame, Fossum 2015 IISW



- XFAB 0.18um 1.8V
- 1376(H) x 768(V) 3.6um 3T CDS
- 119uV/e-, 2e- rms, ~5.2e- threshold
- 768KSa/s
- 1 Gb/s data rate
- Whole chip incl. pads 20mW
- ADCs 2.6mW
- Energy 2.5pJ/b

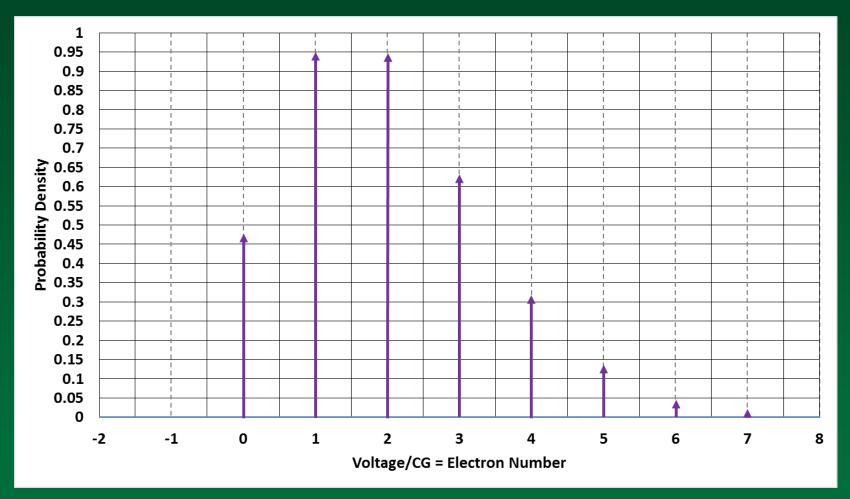


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Poisson Distribution (scaled)

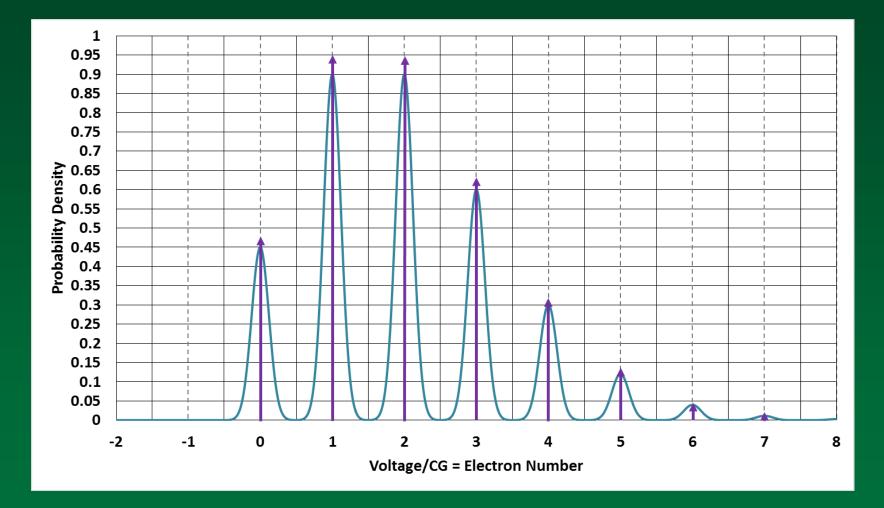
H=2



$$P[k] = \frac{e^{-H} H^k}{k!}, k = 0, 1, 2, 3 \dots$$



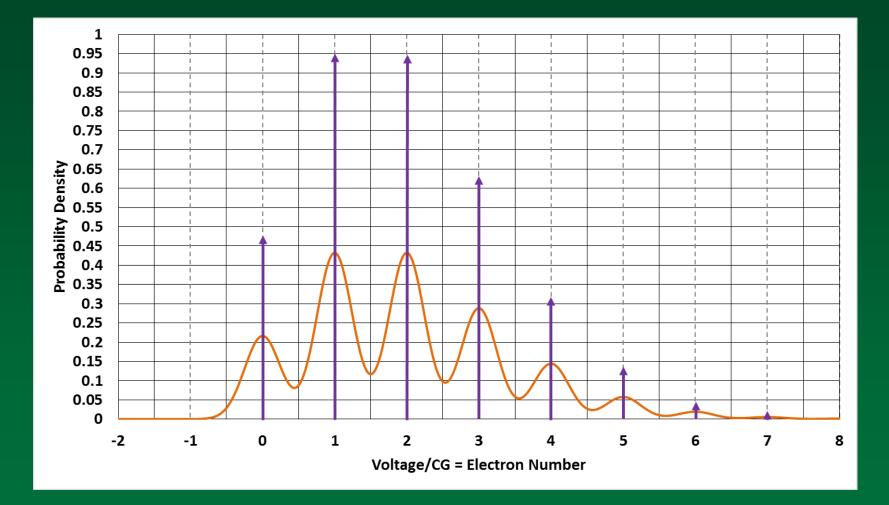
Broadened by 0.12e- rms read noise







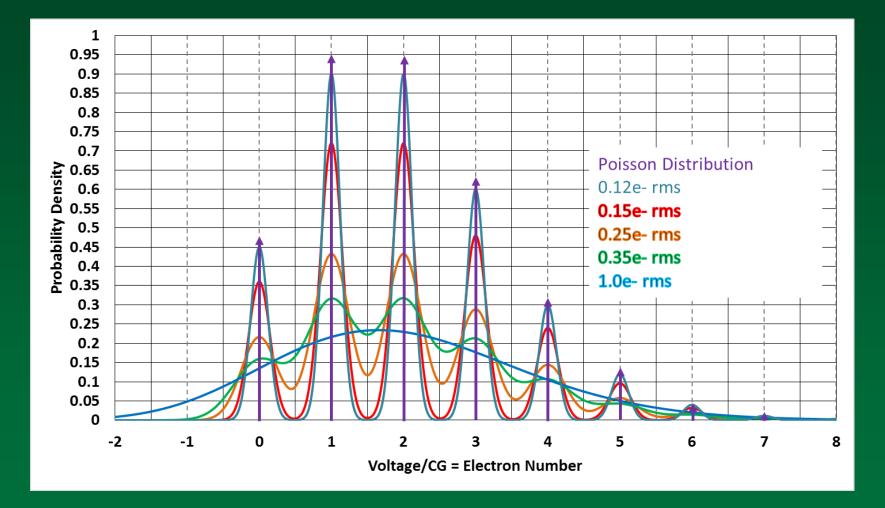
Broadened by 0.25e- rms read noise



Model



Probability Distribution for Various Levels of Read Noise

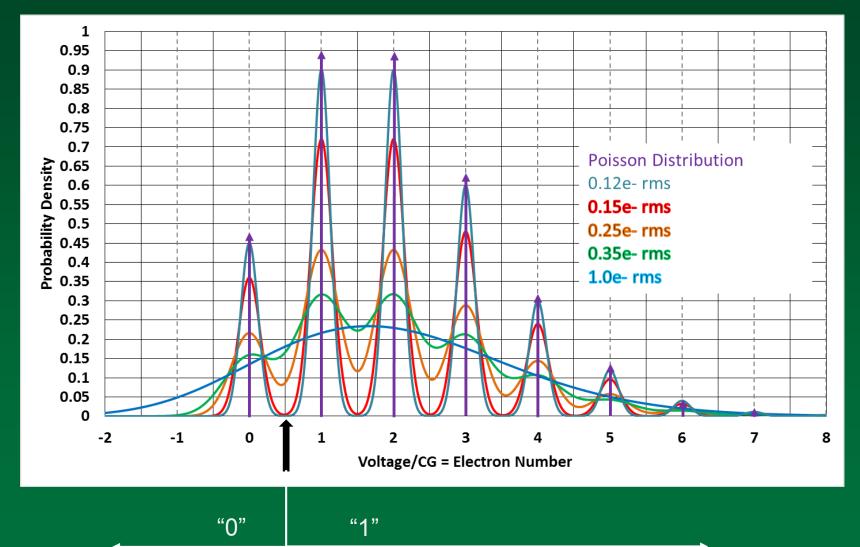


Model





Single-bit QIS



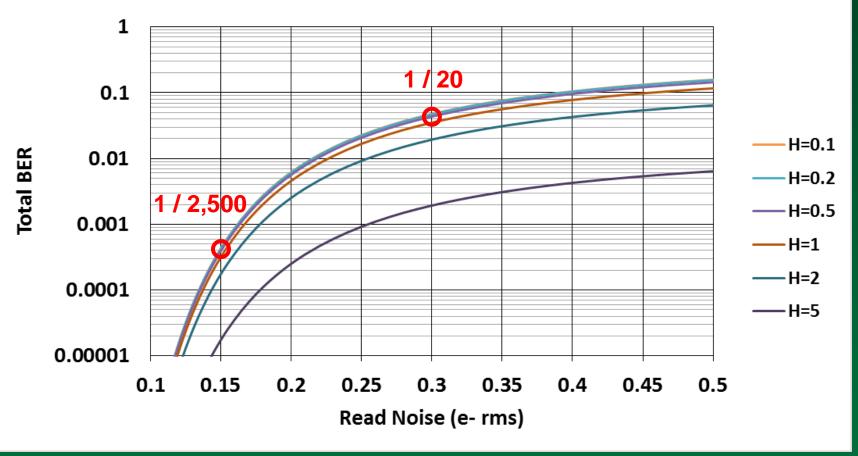
-50-





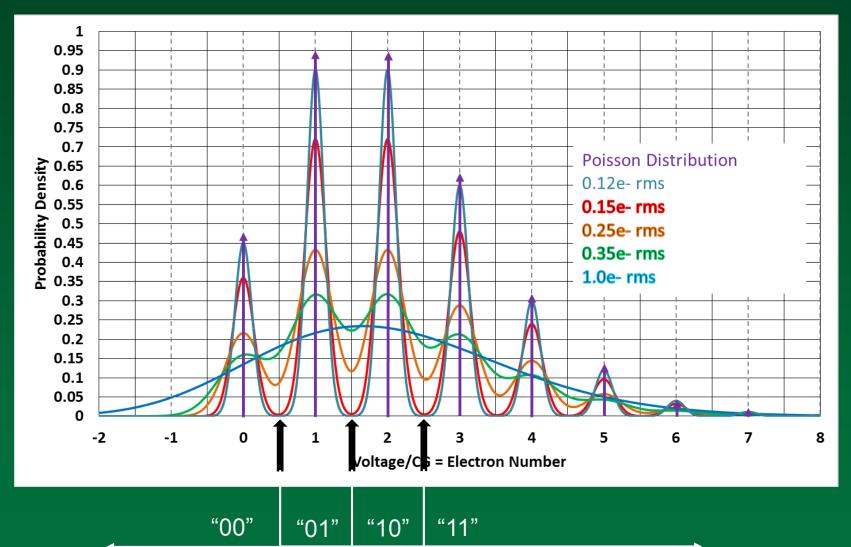
BER vs. Read Noise

Single-Bit QIS BER





Multi-bit QIS (e.g. 2-bit)







Single Bit v. Multi-bit

Single Bit

- Each jot produces 1 bit
- 1 bit ADC

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- For same flux capacity, need higher frame rate readout
- Conceptual simplicity
- Easier on chip digital electronics

Multi-bit

- Each jot produces n bits
- n-bit ADC
- For same flux capacity, lower relative frame rate 1/2⁽ⁿ⁻¹⁾
- Like current CMOS APS but low FW capacity and high conversion gain





Jot Device Considerations

General targets:

- 200 nm device in 22 nm process node ("10L")
- 0.15e- rms read noise or less
- High conversion gain > 1 mV/e- (per photoelectron)
- Low active pixel transistor noise <150 uV rms
- Small storage well capacity ~1-100 e-
- Complete reset for low noise
- Low dark current ~ 1 e-/s
- Not too difficult to fabricate in CIS line

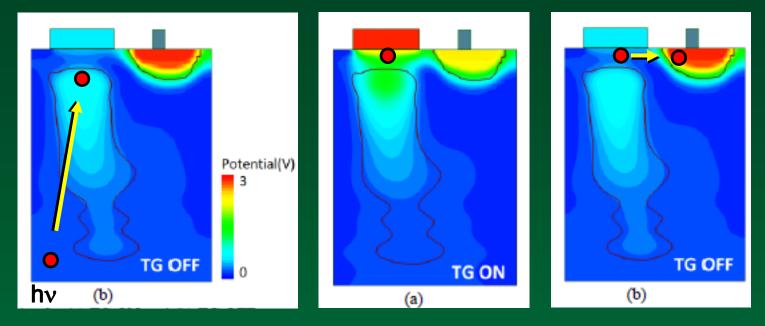
Candidate devices

- Single photon avalanche detector (SPAD)
- Single electron FET
- Bipolar jot
- Pump gate jot
- JFET jot





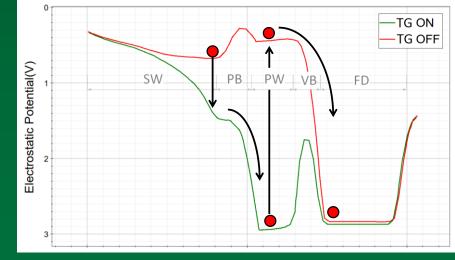
Pump-Gate Jot



Fabricated in TSMC 65nm BSI CIS

1.4um pitch

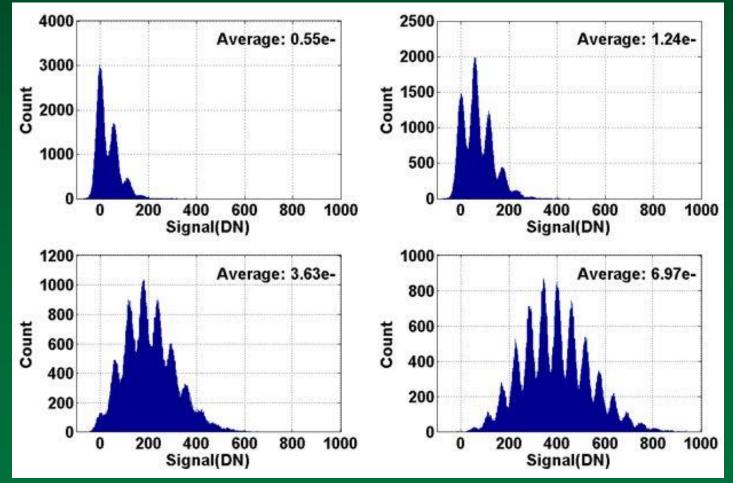
Ma and Fossum 2014 IEDM, 2015 JEDS, 2015 EDL





Experimental Data Photon-Counting Histograms

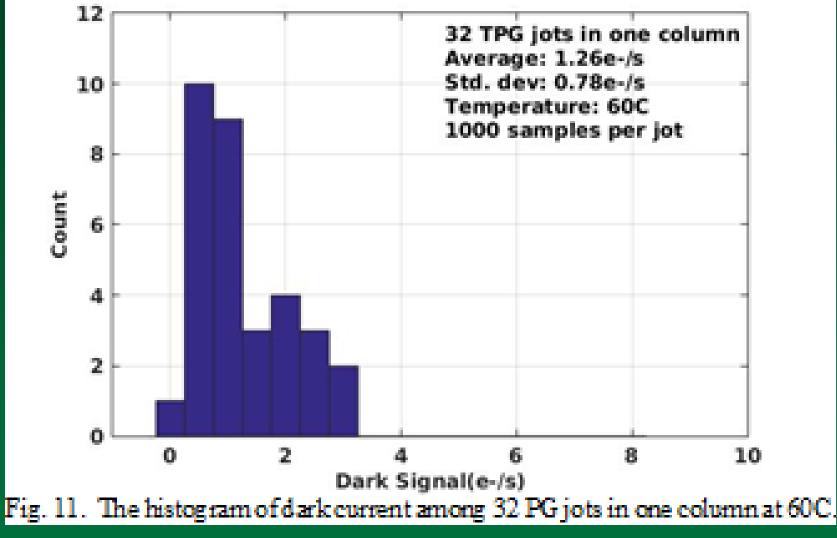
200k reads of same jot, ~0.28e- rms read noise, 120uV rms, 430uV/e-, ~60DN/e-Room Temperature, No Avalanche, Single CDS readout



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Dark Current

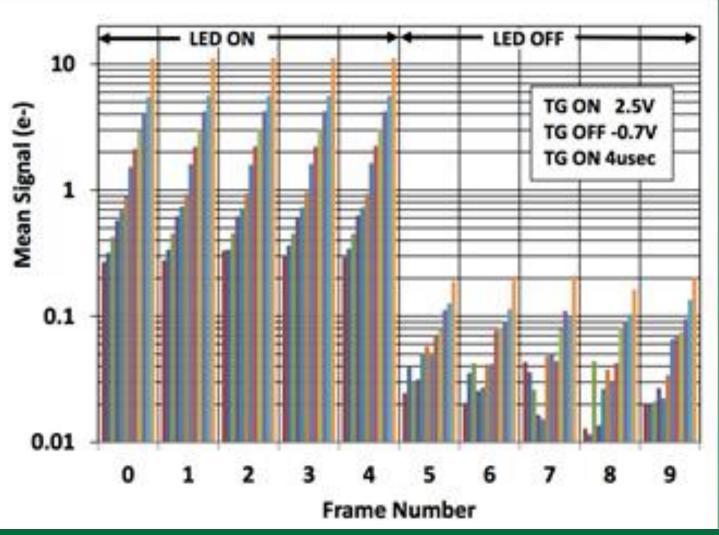


Ma, Starkey, Rao, Odame and Fossum, submitted to IEEE JEDS Aug 2015

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Lag



Ma, Starkey, Rao, Odame and Fossum, submitted to IEEE JEDS Aug 2015



Experimental Data Photon-Counting Histograms

200k reads of same jot, ~0.22e- rms read noise, 93uV rms, 423uV/e-, ~60DN/e-Room Temperature, No Avalanche, Single CDS readout

